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#### What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

#### Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

Product Status	Obsolete
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	72MHz
Connectivity	CANbus, I <sup>2</sup> C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	DMA, Motor Control PWM, PDR, POR, PVD, PWM, Temp Sensor, WDT
Number of I/O	26
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	10K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 10x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	36-VFQFN Exposed Pad
Supplier Device Package	36-VFQFPN (6x6)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f103t6u6

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

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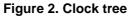


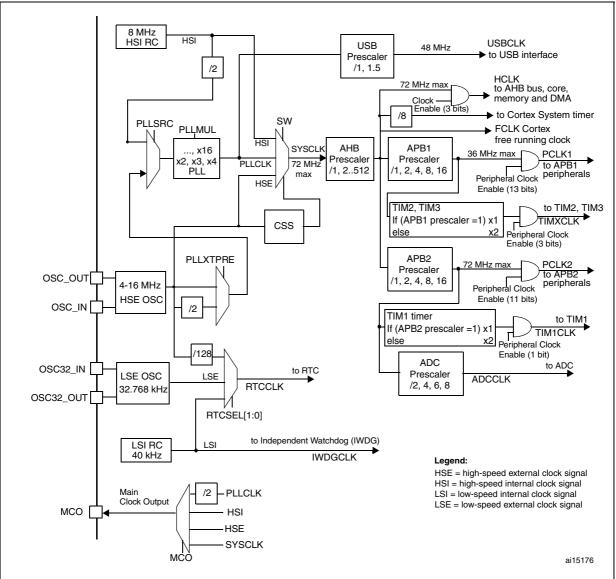
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#### STM32F103x4, STM32F103x6





- 1. When the HSI is used as a PLL clock input, the maximum system clock frequency that can be achieved is 64 MHz.
- 2. For the USB function to be available, both HSE and PLL must be enabled, with USBCLK running at 48  $\,$  MHz.
- 3. To have an ADC conversion time of 1  $\mu s,$  APB2 must be at 14 MHz, 28 MHz or 56 MHz.



### 2.2 Full compatibility throughout the family

The STM32F103xx is a complete family whose members are fully pin-to-pin, software and feature compatible. In the reference manual, the STM32F103x4 and STM32F103x6 are identified as low-density devices, the STM32F103x8 and STM32F103xB are referred to as medium-density devices, and the STM32F103xC, STM32F103xD and STM32F103xE are referred to as high-density devices.

Low- and high-density devices are an extension of the STM32F103x8/B devices, they are specified in the STM32F103x4/6 and STM32F103xC/D/E datasheets, respectively. Low-density devices feature lower Flash memory and RAM capacities, less timers and peripherals. High-density devices have higher Flash memory and RAM capacities, and additional peripherals like SDIO, FSMC, I<sup>2</sup>S and DAC, while remaining fully compatible with the other members of the STM32F103xx family.

The STM32F103x4, STM32F103x6, STM32F103xC, STM32F103xD and STM32F103xE are a drop-in replacement for STM32F103x8/B medium-density devices, allowing the user to try different memory densities and providing a greater degree of freedom during the development cycle.

Moreover, the STM32F103xx performance line family is fully compatible with all existing STM32F101xx access line and STM32F102xx USB access line devices.

		lensity vices		-density ices	High-density devices		,	
Pinout	16 KB Flash	32 KB Flash <sup>(1)</sup>	64 KB Flash	128 KB Flash	256 KB Flash	384 KB Flash	512 KB Flash	
	6 KB RAM	10 KB RAM	20 KB RAM	20 KB RAM	48 KB RAM	64 KB RAM	64 KB RAM	
144	-	-	-	-	5 × USARTs			
100	-	-			$4 \times 16$ -bit timers, $2 \times basic timers$ $3 \times SPIs$ , $2 \times I^2Ss$ , $2 \times I2Cs$			
64	2 × USART 2 × 16-bit ti 1 × SPI, 1 ×	mers	$3 \times USARTs$ $3 \times 16$ -bit tim $2 \times SPIs$ , $2 \times CAN$	<sup>12</sup> Cs, USB,	3 × ADCs, 2	2 × PWM time × DACs, 1 × and 144 pins)	SDIO	
48	CAN, 1 × P		CAN, 1 × PW 2 × ADCs	nvi umer	-	-	-	
36	2 × ADCs				-	-	-	

Table 3. STM32F103xx family

 For orderable part numbers that do not show the A internal code after the temperature range code (6 or 7), the reference datasheet for electrical characteristics is that of the STM32F103x8/B medium-density devices.



This hardware block provides flexible interrupt management features with minimal interrupt latency.

#### 2.3.6 External interrupt/event controller (EXTI)

The external interrupt/event controller consists of 19 edge detector lines used to generate interrupt/event requests. Each line can be independently configured to select the trigger event (rising edge, falling edge, both) and can be masked independently. A pending register maintains the status of the interrupt requests. The EXTI can detect an external line with a pulse width shorter than the Internal APB2 clock period. Up to 51 GPIOs can be connected to the 16 external interrupt lines.

#### 2.3.7 Clocks and startup

System clock selection is performed on startup, however the internal RC 8 MHz oscillator is selected as default CPU clock on reset. An external 4-16 MHz clock can be selected, in which case it is monitored for failure. If failure is detected, the system automatically switches back to the internal RC oscillator. A software interrupt is generated if enabled. Similarly, full interrupt management of the PLL clock entry is available when necessary (for example on failure of an indirectly used external crystal, resonator or oscillator).

Several prescalers allow the configuration of the AHB frequency, the high-speed APB (APB2) and the low-speed APB (APB1) domains. The maximum frequency of the AHB and the high-speed APB domains is 72 MHz. The maximum allowed frequency of the low-speed APB domain is 36 MHz. See *Figure 2* for details on the clock tree.

#### 2.3.8 Boot modes

At startup, boot pins are used to select one of three boot options:

- Boot from User Flash
- Boot from System Memory
- Boot from embedded SRAM

The boot loader is located in System Memory. It is used to reprogram the Flash memory by using USART1. For further details please refer to AN2606.

#### 2.3.9 Power supply schemes

- $V_{DD} = 2.0$  to 3.6 V: external power supply for I/Os and the internal regulator. Provided externally through  $V_{DD}$  pins.
- $V_{SSA}$ ,  $V_{DDA} = 2.0$  to 3.6 V: external analog power supplies for ADC, reset blocks, RCs and PLL (minimum voltage to be applied to  $V_{DDA}$  is 2.4 V when the ADC is used).  $V_{DDA}$  and  $V_{SSA}$  must be connected to  $V_{DD}$  and  $V_{SS}$ , respectively.
- V<sub>BAT</sub> = 1.8 to 3.6 V: power supply for RTC, external clock 32 kHz oscillator and backup registers (through power switch) when V<sub>DD</sub> is not present.

For more details on how to connect power pins, refer to *Figure 11: Power supply scheme*.

#### 2.3.10 Power supply supervisor

The device has an integrated power-on reset (POR)/power-down reset (PDR) circuitry. It is always active, and ensures proper operation starting from/down to 2 V. The device remains



in reset mode when  $V_{DD}$  is below a specified threshold,  $V_{POR/PDR}$ , without the need for an external reset circuit.

The device features an embedded programmable voltage detector (PVD) that monitors the  $V_{DD}/V_{DDA}$  power supply and compares it to the  $V_{PVD}$  threshold. An interrupt can be generated when  $V_{DD}/V_{DDA}$  drops below the  $V_{PVD}$  threshold and/or when  $V_{DD}/V_{DDA}$  is higher than the  $V_{PVD}$  threshold. The interrupt service routine can then generate a warning message and/or put the MCU into a safe state. The PVD is enabled by software.

Refer to Table 11: Embedded reset and power control block characteristics for the values of  $V_{POR/PDR}$  and  $V_{PVD}$ .

#### 2.3.11 Voltage regulator

The regulator has three operation modes: main (MR), low power (LPR) and power down.

- MR is used in the nominal regulation mode (Run)
- LPR is used in the Stop mode
- Power down is used in Standby mode: the regulator output is in high impedance: the kernel circuitry is powered down, inducing zero consumption (but the contents of the registers and SRAM are lost)

This regulator is always enabled after reset. It is disabled in Standby mode, providing high impedance output.

#### 2.3.12 Low-power modes

The STM32F103xx performance line supports three low-power modes to achieve the best compromise between low power consumption, short startup time and available wakeup sources:

• Sleep mode

In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs.

• Stop mode

The Stop mode achieves the lowest power consumption while retaining the content of SRAM and registers. All clocks in the 1.8 V domain are stopped, the PLL, the HSI RC and the HSE crystal oscillators are disabled. The voltage regulator can also be put either in normal or in low power mode.

The device can be woken up from Stop mode by any of the EXTI line. The EXTI line source can be one of the 16 external lines, the PVD output, the RTC alarm or the USB wakeup.

• Standby mode

The Standby mode is used to achieve the lowest power consumption. The internal voltage regulator is switched off so that the entire 1.8 V domain is powered off. The PLL, the HSI RC and the HSE crystal oscillators are also switched off. After entering Standby mode, SRAM and register contents are lost except for registers in the Backup domain and Standby circuitry.

The device exits Standby mode when an external reset (NRST pin), an IWDG reset, a rising edge on the WKUP pin, or an RTC alarm occurs.

The RTC, the IWDG, and the corresponding clock sources are not stopped by entering Stop or Standby mode.



Note:

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#### 2.3.13 DMA

The flexible 7-channel general-purpose DMA is able to manage memory-to-memory, peripheral-to-memory and memory-to-peripheral transfers. The DMA controller supports circular buffer management avoiding the generation of interrupts when the controller reaches the end of the buffer.

Each channel is connected to dedicated hardware DMA requests, with support for software trigger on each channel. Configuration is made by software and transfer sizes between source and destination are independent.

The DMA can be used with the main peripherals: SPI, I<sup>2</sup>C, USART, general-purpose and advanced-control timers TIMx and ADC.

#### 2.3.14 RTC (real-time clock) and backup registers

The RTC and the backup registers are supplied through a switch that takes power either on  $V_{DD}$  supply when present or through the  $V_{BAT}$  pin. The backup registers are ten 16-bit registers used to store 20 bytes of user application data when  $V_{DD}$  power is not present.

The real-time clock provides a set of continuously running counters which can be used with suitable software to provide a clock calendar function, and provides an alarm interrupt and a periodic interrupt. It is clocked by a 32.768 kHz external crystal, resonator or oscillator, the internal low-power RC oscillator or the high-speed external clock divided by 128. The internal low-power RC has a typical frequency of 40 kHz. The RTC can be calibrated using an external 512 Hz output to compensate for any natural crystal deviation. The RTC features a 32-bit programmable counter for long-term measurement using the Compare register to generate an alarm. A 20-bit prescaler is used for the time base clock and is by default configured to generate a time base of 1 second from a clock at 32.768 kHz.

#### 2.3.15 Timers and watchdogs

The low-density STM32F103xx performance line devices include an advanced-control timer, two general-purpose timers, two watchdog timers and a SysTick timer.

Table 4 compares the features of the advanced-control and general-purpose timers.

Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
TIM1	16-bit	Up, down, up/down	Any integer between 1 and 65536	Yes	4	Yes

#### Table 4. Timer feature comparison



#### Advanced-control timer (TIM1)

The advanced-control timer (TIM1) can be seen as a three-phase PWM multiplexed on 6 channels. It has complementary PWM outputs with programmable inserted dead-times. It can also be seen as a complete general-purpose timer. The 4 independent channels can be used for

- Input capture
- Output compare
- PWM generation (edge- or center-aligned modes)
- One-pulse mode output

If configured as a general-purpose 16-bit timer, it has the same features as the TIMx timer. If configured as the 16-bit PWM generator, it has full modulation capability (0-100%).

In debug mode, the advanced-control timer counter can be frozen and the PWM outputs disabled to turn off any power switch driven by these outputs.

Many features are shared with those of the general-purpose TIM timers which have the same architecture. The advanced-control timer can therefore work together with the TIM timers via the Timer Link feature for synchronization or event chaining.

#### General-purpose timers (TIMx)

There are up to two synchronizable general-purpose timers embedded in the STM32F103xx performance line devices. These timers are based on a 16-bit auto-reload up/down counter, a 16-bit prescaler and feature 4 independent channels each for input capture/output compare, PWM or one-pulse mode output. This gives up to 12 input captures/output compares/PWMs on the largest packages.

The general-purpose timers can work together with the advanced-control timer via the Timer Link feature for synchronization or event chaining. Their counter can be frozen in debug mode. Any of the general-purpose timers can be used to generate PWM outputs. They all have independent DMA request generation.

These timers are capable of handling quadrature (incremental) encoder signals and the digital outputs from 1 to 3 hall-effect sensors.

#### Independent watchdog

The independent watchdog is based on a 12-bit downcounter and 8-bit prescaler. It is clocked from an independent 40 kHz internal RC and as it operates independently of the main clock, it can operate in Stop and Standby modes. It can be used either as a watchdog to reset the device when a problem occurs, or as a free-running timer for application timeout management. It is hardware- or software-configurable through the option bytes. The counter can be frozen in debug mode.

#### Window watchdog

The window watchdog is based on a 7-bit downcounter that can be set as free-running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the main clock. It has an early warning interrupt capability and the counter can be frozen in debug mode.



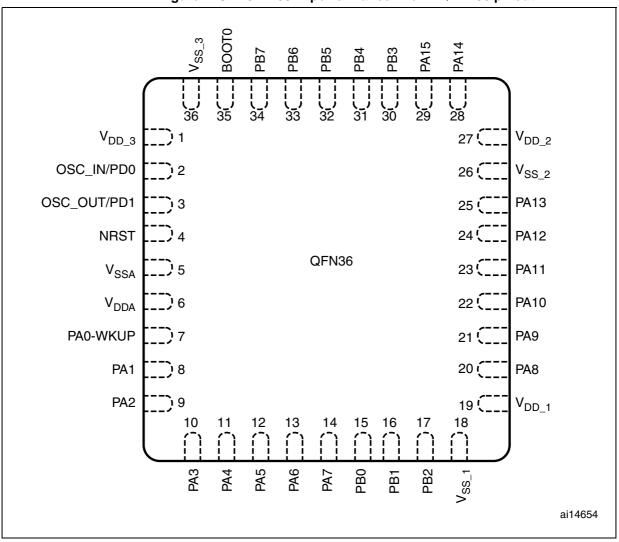
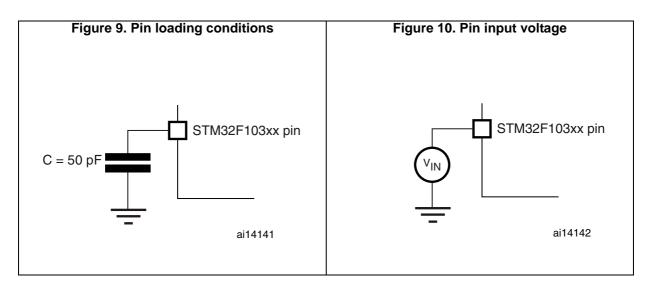
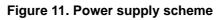


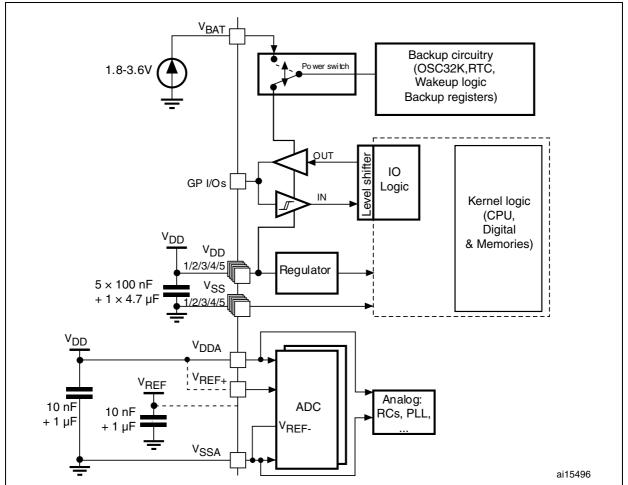
Figure 7. STM32F103xx performance line VFQFPN36 pinout





### 5.1.6 Power supply scheme





**Caution:** In *Figure 11*, the 4.7  $\mu$ F capacitor must be connected to V<sub>DD3</sub>.



Cumhal	Devementer	Conditions	4	Max	l In:t	
Symbol	Parameter	Conditions	fHCLK	T <sub>A</sub> = 85 °C	T <sub>A</sub> = 105 °C	Unit
			72 MHz	26	27	
	Supply current in DD Sleep mode		48 MHz	17	18	
		External clock <sup>(2)</sup> , all	36 MHz	14	15	
		peripherals enabled	24 MHz	10	11	
			16 MHz	7	8	
			8 MHz	4	5	~ ^
DD		External clock <sup>(2)</sup> , all	72 MHz	7.5	8	mA
			48 MHz	6	6.5	
			36 MHz	5	5.5	
		peripherals disabled	24 MHz	4.5	5	
			16 MHz	4	4.5	
1			8 MHz	3	4	

## Table 15. Maximum current consumption in Sleep mode, code running from Flash or RAM

1. based on characterization, tested in production at  $V_{\text{DD}\ \text{max}},\,f_{\text{HCLK}}$  max with peripherals enabled.

2. External clock is 8 MHz and PLL is on when  $f_{\text{HCLK}}$  > 8 MHz.



### 5.3.6 External clock source characteristics

#### High-speed external user clock generated from an external source

The characteristics given in *Table 20* result from tests performed using an high-speed external clock source, and under ambient temperature and supply voltage conditions summarized in *Table 9*.

#### Table 20. High-speed external user clock characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
f <sub>HSE_ext</sub>	User external clock source frequency <sup>(1)</sup>		1	8	25	MHz
V <sub>HSEH</sub>	OSC_IN input pin high level voltage		$0.7 V_{DD}$	-	$V_{DD}$	V
V <sub>HSEL</sub>	OSC_IN input pin low level voltage		$V_{SS}$	-	$0.3V_{DD}$	v
t <sub>w(HSE)</sub> t <sub>w(HSE)</sub>	OSC_IN high or low time <sup>(1)</sup>	-	5	-	-	ns
t <sub>r(HSE)</sub> t <sub>f(HSE)</sub>	OSC_IN rise or fall time <sup>(1)</sup>		-	-	20	115
$C_{in(HSE)}$	OSC_IN input capacitance <sup>(1)</sup>	-	-	5	-	pF
DuCy <sub>(HSE)</sub>	Duty cycle	-	45	-	55	%
۱L	OSC_IN Input leakage current	$V_{SS} \leq$				

#### Low-speed external user clock generated from an external source

The characteristics given in *Table 21* result from tests performed using an low-speed external clock source, and under ambient temperature and supply voltage conditions summarized in *Table 9*.



Symbol	Parameter	Conditions	Min	Тур	Max	Unit
f <sub>OSC_IN</sub>	Oscillator frequency	-	4	8	16	MHz
R <sub>F</sub>	Feedback resistor	-	-	200	-	kΩ
С	Recommended load capacitance versus equivalent serial resistance of the crystal $(R_S)^{(3)}$	R <sub>S</sub> = 30 Ω	-	30	-	pF
i <sub>2</sub>	HSE driving current	$V_{DD}$ = 3.3 V, $V_{IN}$ = $V_{SS}$ with 30 pF load	-	-	1	mA
9 <sub>m</sub>	Oscillator transconductance	Startup	25	-	-	mA/V
$t_{\rm SU(HSE}^{(4)}$	startup time	V <sub>DD</sub> is stabilized	-	2	-	ms

Table 22. HSE 4-16 MHz oscillato	r characteristics <sup>(1) (2)</sup>
----------------------------------	--------------------------------------

1. Resonator characteristics given by the crystal/ceramic resonator manufacturer.

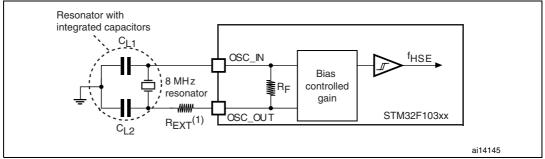
2. Based on characterization, not tested in production.

3. The relatively low value of the RF resistor offers a good protection against issues resulting from use in a humid environment, due to the induced leakage and the bias condition change. However, it is recommended to take this point into account if the MCU is used in tough humidity conditions.

 t<sub>SU(HSE)</sub> is the startup time measured from the moment it is enabled (by software) to a stabilized 8 MHz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer

For  $C_{L1}$  and  $C_{L2}$ , it is recommended to use high-quality external ceramic capacitors in the 5 pF to 25 pF range (typ.), designed for high-frequency applications, and selected to match the requirements of the crystal or resonator (see *Figure 21*).  $C_{L1}$  and  $C_{L2}$  are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of  $C_{L1}$  and  $C_{L2}$ . PCB and MCU pin capacitance must be included (10 pF can be used as a rough estimate of the combined pin and board capacitance) when sizing  $C_{L1}$  and  $C_{L2}$ . Refer to the application note AN2867 "Oscillator design guide for ST microcontrollers" available from the ST website www.st.com.





1. R<sub>EXT</sub> value depends on the crystal characteristics.

#### Low-speed external clock generated from a crystal/ceramic resonator

The low-speed external (LSE) clock can be supplied with a 32.768 kHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in *Table 23*. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization



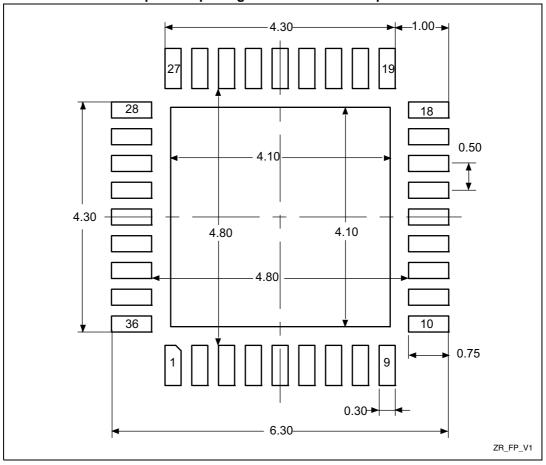
Symbol		millimeters			inches <sup>(1)</sup>		
Symbol	Min	Тур	Мах	Min	Тур	Max	
А	0.800	0.900	1.000	0.0315	0.0354	0.0394	
A1	-	0.020	0.050	-	0.0008	0.0020	
A2	-	0.650	1.000	-	0.0256	0.0394	
A3	-	0.200	-	-	0.0079	-	
b	0.180	0.230	0.300	0.0071	0.0091	0.0118	
D	5.875	6.000	6.125	0.2313	0.2362	0.2411	
D2	1.750	3.700	4.250	0.0689	0.1457	0.1673	
E	5.875	6.000	6.125	0.2313	0.2362	0.2411	
E2	1.750	3.700	4.250	0.0689	0.1457	0.1673	
е	0.450	0.500	0.550	0.0177	0.0197	0.0217	
L	0.350	0.550	0.750	0.0138	0.0217	0.0295	
К	0.250	-	-	0.0098	-	-	
ddd	-	-	0.080	-	-	0.0031	

# Table 51. VFQFPN36 - 36-pin, 6x6 mm, 0.5 mm pitch very thin profile fine pitchquad flat package mechanical data

1. Values in inches are converted from mm and rounded to 4 decimal digits.







# Figure 39. VFQFPN36 - 36-pin, 6x6 mm, 0.5 mm pitch very thin profile fine pitch quad flat package recommended footprint

1. Dimensions are expressed in millimeters.

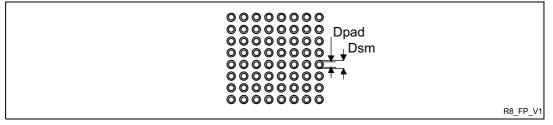


## Table 54. TFBGA64 – 64-ball, 5 x 5 mm, 0.5 mm pitch, thin profile fine pitch ballgrid array package mechanical data (continued)

Symbol	millimeters				inches <sup>(1)</sup>	
Symbol	Min	Тур	Max	Min	Тур	Мах
е	-	0.500	-	-	0.0197	-
F	-	0.750	-	-	0.0295	-
ddd	-	-	0.080	-	-	0.0031
eee	-	-	0.150	-	-	0.0059
fff	-	-	0.050	-	-	0.0020

1. Values in inches are converted from mm and rounded to 4 decimal digits.

# Figure 48. TFBGA64 – 64-ball, 5 x 5 mm, 0.5 mm pitch, thin profile fine pitch ball grid array, recommended footprint



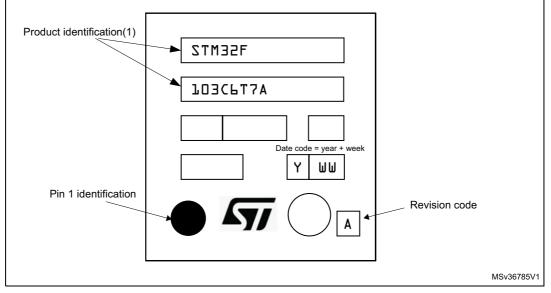
#### Table 55. TFBGA64 recommended PCB design rules (0.5 mm pitch BGA)

Dimension	Recommended values
Pitch	0.5
Dpad	0.280 mm
Dsm	0.370 mm typ. (depends on the soldermask registration tolerance)
Stencil opening	0.280 mm
Stencil thickness	Between 0.100 mm and 1.125 mm
Pad trace width	0.100 mm



#### **Device Marking for LQFP48**

The following figure gives an example of topside marking orientation versus ball 1 identifier location.





 Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

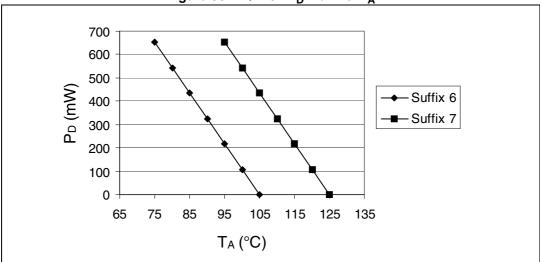


Using the values obtained in *Table*  $57 T_{Jmax}$  is calculated as follows:

- For LQFP64, 45 °C/W
- T<sub>Jmax</sub> = 115 °C + (45 °C/W × 134 mW) = 115 °C + 6.03 °C = 121.03 °C

This is within the range of the suffix 7 version parts (–40 <  $T_J$  < 125 °C).

In this case, parts must be ordered at least with the temperature range suffix 7 (see *Table 58: Ordering information scheme*).







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